

1,5-Dichloro-2,4-dinitrobenzene

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Key indicators

Single-crystal X-ray study

$T = 298$ K

Mean $\sigma(\text{C}-\text{C}) = 0.006$ Å

R factor = 0.061

wR factor = 0.163

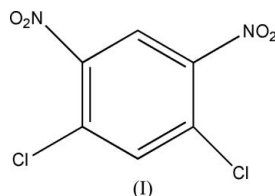
Data-to-parameter ratio = 13.6

For details of how these key indicators were
automatically derived from the article, see
<http://journals.iucr.org/e>.

In the title compound, $\text{C}_6\text{H}_2\text{Cl}_2\text{N}_2\text{O}_4$, the two nitro groups are twisted away from the plane of the aromatic ring. Intermolecular short $\text{Cl}\cdots\text{O}$ and $\text{Cl}\cdots\text{Cl}$ contacts are observed in the crystal structure.

Comment

1,5-Dichloro-2,4-dinitrobenzene, (I), is an important intermediate which can be used for the syntheses of dyes and pesticides (Lv, 1995). We report here the crystal structure of (I).



The molecular structure of (I) is shown in Fig. 1. The bond lengths and angles are within normal ranges (Allen *et al.*, 1987). The $\text{O}-\text{N}-\text{C}-\text{C}$ torsion angles (Table 1) indicate that the two nitro groups are twisted away from the plane of the attached ring.

Short intermolecular $\text{Cl}\cdots\text{O}$ [$\text{Cl}1\cdots\text{O}4(2-x, 2-y, 1-z) = 3.158(5)$ Å] and $\text{Cl}\cdots\text{Cl}$ [$\text{Cl}2\cdots\text{Cl}2(1-x, -y, 1-z) = 3.261(2)$ Å] contacts are observed in the crystal structure.

Experimental

Compound (I) was prepared according to the reported procedure of Lv (1995). Single crystals suitable for X-ray diffraction were obtained by slow evaporation of an ethanol (50 ml) solution of (I) (1.0 g).

Crystal data

$\text{C}_6\text{H}_2\text{Cl}_2\text{N}_2\text{O}_4$

$M_r = 237.00$

Monoclinic, $P2_1/c$

$a = 9.5900(19)$ Å

$b = 6.5860(13)$ Å

$c = 14.751(3)$ Å

$\beta = 106.86(3)^\circ$

$V = 891.6(3)$ Å³

$Z = 4$

$D_x = 1.766$ Mg m⁻³

Mo $K\alpha$ radiation

$\mu = 0.72$ mm⁻¹

$T = 298(2)$ K

Block, yellow

$0.30 \times 0.20 \times 0.10$ mm

Data collection

Enraf-Nonius CAD-4
diffractometer

$\omega/2\theta$ scans

Absorption correction: ψ scan
(North *et al.*, 1968)

$T_{\min} = 0.814$, $T_{\max} = 0.932$

1845 measured reflections

1739 independent reflections

1065 reflections with $I > 2\sigma(I)$

$R_{\text{int}} = 0.033$

$\theta_{\max} = 26.0^\circ$

3 standard reflections

every 200 reflections

intensity decay: none

Refinement

Refinement on F^2
 $R[F^2 > 2\sigma(F^2)] = 0.061$
 $wR(F^2) = 0.163$
 $S = 1.04$
 1739 reflections
 128 parameters
 H-atom parameters constrained

$w = 1/[\sigma^2(F_o^2) + (0.0612P)^2 + 0.8029P]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\max} = 0.001$
 $\Delta\rho_{\max} = 0.39 \text{ e } \text{Å}^{-3}$
 $\Delta\rho_{\min} = -0.21 \text{ e } \text{Å}^{-3}$
 Extinction correction: *SHELXL97*
 (Sheldrick, 1997)
 Extinction coefficient: 0.081 (7)

Table 1

Selected torsion angles ($^\circ$).

O4–N2–C2–C3	–135.2 (5)	O2–N1–C4–C3	–33.8 (6)
O3–N2–C2–C3	42.0 (7)	O1–N1–C4–C3	144.9 (4)
O4–N2–C2–C1	45.8 (7)	O2–N1–C4–C5	145.8 (4)
O3–N2–C2–C1	–137.0 (5)	O1–N1–C4–C5	–35.6 (6)

H atoms were positioned geometrically ($\text{C–H} = 0.93 \text{ \AA}$) and constrained to ride on their parent atoms, with $U_{\text{iso}}(\text{H}) = 1.2U_{\text{eq}}(\text{C})$.

Data collection: *CAD-4 Software* (Enraf–Nonius, 1989); cell refinement: *CAD-4 Software*; data reduction: *XCAD4* (Harms & Wocadlo, 1995); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL* (Bruker, 2000); software used to prepare material for publication: *SHELXTL*.

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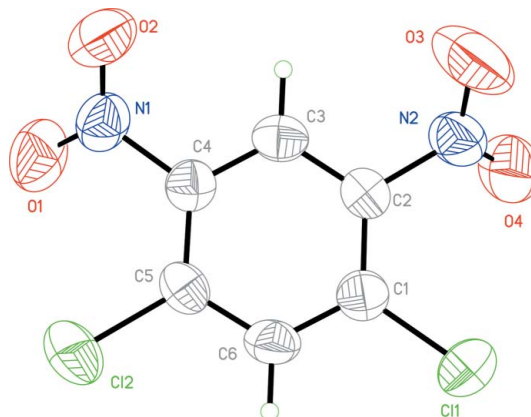


Figure 1

The molecular structure of (I), showing the atom-numbering scheme. Displacement ellipsoids are drawn at the 50% probability level.

References

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